SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

- **Highest Performance Fixed-Point Digital** Signal Processor (DSP) SM320C6201
 - 6.67-ns Instruction Cycle Time
 - 150-MHz Clock Rate
 - Eight 32-Bit Instructions/Cycle
 - 1200 MIPS
- **Highest Performance Fixed-Point Digital** Signal Processor (DSP) SMJ320C6201B
 - 6.67-ns Instruction Cycle Time
 - 150-MHz Clock Rate
 - Eight 32-Bit Instructions/Cycle
 - 1200 MIPS
- VelociTI[™] Advanced Very Long Instruction Word (VLIW) 'C6200 CPU Core
 - Eight Independent Functional Units:
 - Six ALUs (32-/40-Bit)
 - Two 16-Bit Multipliers (32-Bit Results)
 - Load-Store Architecture With 32 32-Bit **General-Purpose Registers**
 - Instruction Packing Reduces Code Size
 - All Instructions Conditional
- Instruction Set Features
 - Byte-Addressable (8-, 16-, 32-Bit Data)
 - 32-Bit Address Range
 - 8-Bit Overflow Protection
 - Saturation
 - Bit-Field Extract, Set, Clear
 - Bit-Counting
 - Normalization
- 1M-Bit On-Chip SRAM
 - 512K-Bit Internal Program/Cache (16K 32-Bit Instructions)
 - 512K-Bit Dual-Access Internal Data (64K Bytes) Organized as a Single Block ('6201)
 - 512K-Bit Dual-Access Internal Data (64K Bytes) Organized as Two Blocks for Improved Concurrency ('6201B)
- 32-Bit External Memory Interface (EMIF)
 - Glueless Interface to Synchronous Memories: SDRAM and SBSRAM
 - Glueless Interface to Asynchronous Memories: SRAM and EPROM
- Four-Channel Bootloading **Direct-Memory-Access (DMA) Controller** with an Auxiliary Channel



GLE and GLP PACKAGES

- **16-Bit Host-Port Interface (HPI)** - Access to Entire Memory Map
- **Two Multichannel Buffered Serial Ports** (McBSPs)
 - Direct Interface to T1/E1, MVIP, SCSA Framers
 - ST-Bus-Switching Compatible
 - Up to 256 Channels Each
 - AC97-Compatible
 - Serial Peripheral Interface (SPI) Compatible (Motorola[™])
- **Two 32-Bit General-Purpose Timers**
- Flexible Phase-Locked Loop (PLL) Clock Generator
- IEEE-1149.1 (JTAG[†]) Boundary-Scan Compatible
- 429-Pin BGA Package (GLE Suffix) ('6201)
- 429-Pin BGA Package (GLP Suffix) ('6201B)
- **CMOS** Technology - 0.25-um/5-Level Metal Process ('6201) - 0.18-μm/5-Level Metal Process ('6201B)
- 3.3-V I/Os, 2.5-V Internal ('6201)
- 3.3-V I/Os, 1.8-V Internal ('6201B)



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

VelociTI is a trademark of Texas Instruments Incorporated. Motorola is a trademark of Motorola, Inc. [†] IEEE Standard 1149.1-1990 Standard-Test-Access Port and Boundary Scan Architecture.

UNLESS OTHERWISE NOTED this document contains PRODUCTION DATA information current as of publication date. Products conform to specifications per the terms of texas instruments standard warranty. Production processing does not necessarily include testing of all



Copyright © 1998, Texas Instruments Incorporated

POST OFFICE BOX 1443 • HOUSTON, TEXAS 77251-1443

SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions						
SIGNAL	SIGNAL					
NAME	NO.	TYPET	DESCRIPTION			
		_	CLOCK/PLL			
CLKIN	A14	I	Clock Input			
CLKOUT1	Y6	0	Clock output at full device speed			
CLKOUT2	V9	0	Clock output at half of device speed			
CLKMODE1	B17		Clock mode select			
CLKMODE0	C17] '	• Selects whether the output clock frequency = input clock freq x4 or x1			
PLLFREQ3	C13		PLL frequency range (3, 2, and 1)			
PLLFREQ2	G11	I I	Selects one of three frequency ranges bounding the CLKOUT1 signal.			
PLLFREQ1	F11		CLKOUT1 frequency determines the 3-bit value for the PLLFREQ pins.			
PLLV [‡]	D12	A§	PLL analog V_{CC} connection for the low-pass filter			
PLLG [‡]	G10	A§	PLL analog GND connection for the low-pass filter			
PLLF	C12	A§	PLL low-pass filter connection to external components and a bypass capacitor			
			JTAG EMULATION			
TMS	K19	I	JTAG test port mode select (features an internal pull-up)			
TDO	R12	O/Z	JTAG test port data out			
TDI	R13	1	JTAG test port data in (features an internal pull-up)			
ТСК	M20	1	JTAG test port clock			
TRST	N18	1	JTAG test port reset (features an internal pull-down)			
EMU1	R20	I/O/Z	Emulation pin 1, pull-up with a dedicated 20-k Ω resistor			
EMU0	T18	I/O/Z	Emulation pin 0, pull-up with a dedicated 20-k Ω resistor			
			CONTROL			
RESET	J20	I	Device reset			
NMI	K21	I	Nonmaskable interrupt Edge-driven (rising edge) 			
EXT_INT7	R16					
EXT_INT6	P20] ,	External interrupts			
EXT_INT5	R15] '	Edge-driven (rising edge)			
EXT_INT4	R18					
IACK	R11	0	Interrupt acknowledge for all active interrupts serviced by the CPU			
INUM3	T19					
INUM2	T20		Active interrupt identification number			
INUM1	T14]	 Valid during rACK for all active interrupts (not just external) Encoding order follows the interrupt service fetch packet ordering 			
INUM0	T16					
LENDIAN	G20	I	If high, selects little-endian byte/half-word addressing order within a word If low, selects big-endian addressing			
PD	D19	0	Power-down mode 3 (active if high)			

[†]I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

[‡] PLLV and PLLG signals are not part of external voltage supply or ground. See the CLOCK/PLL documentation for information on how to connect those pins.

§ A = Analog Signal (PLL Filter)



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions (Continued)				
SIGNAL		TYPET	DESCRIPTION	
NAME	NO.	TIPET	DESCRIPTION	
		_	HOST PORT INTERFACE (HPI)	
HINT	H2	O/Z	Host interrupt (from DSP to host)	
HCNTL1	J6	I	Host control – selects between control, address or data registers	
HCNTL0	H6	I	Host control – selects between control, address or data registers	
HHWIL	E4	I	Host halfword select – first or second halfword (not necessarily high or low order)	
HBE1	G6	I	Host byte select within word or half-word	
HBE0	F6	I	Host byte select within word or half-word	
HR/W	D4	I	Host read or write select	
HD15	D11			
HD14	B11	1		
HD13	A11	1		
HD12	G9	1		
HD11	D10	1		
HD10	A10	1		
HD9	C10	1	Host port data (used for transfer of data, address and control)	
HD8	B9	1/0/7		
HD7	F9	1/0/2		
HD6	C9	1		
HD5	A9	1		
HD4	B8	1		
HD3	D9	1		
HD2	D8	1		
HD1	B7	1		
HD0	C7	1		
HAS	L6	I	Host address strobe	
HCS	C5	I	Host chip select	
HDS1	C4	I	Host data strobe 1	
HDS2	K6	I	Host data strobe 2	
HRDY	H3	0	Host ready (from DSP to host)	
			BOOT MODE	
BOOTMODE4	B16			
BOOTMODE3	G14]		
BOOTMODE2	F15		Boot mode	
BOOTMODE1	C18]		
BOOTMODE0	D17			

 † I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions (Continued)			
SIGNA	L	TYPET	DESCRIPTION
NAME	NO.		
		El	MIF – CONTROL SIGNALS COMMON TO ALL TYPES OF MEMORY
CE3	Y5	O/Z	
CE2	V3	O/Z	Memory space enables
CE1	T6	O/Z	Enabled by bits 24 and 25 of the word address
CE0	U2	O/Z	Only one asserted during any external data access
BE3	R8	O/Z	Byte enable control
BE2	Т3	O/Z	Decoded from the two lowest bits of the internal address
BE1	T2	O/Z	Byte write enables for most types of memory
BE0	R2	O/Z	Can be directly connected to SDRAM read and write mask signal (SDQM)
	-		EMIF – ADDRESS
EA21	L4	1	
EA20	L3	1	
EA19	J2	1	
EA18	J1	1	
EA17	K1	1	
EA16	K2	1	
EA15	L2	1	
EA14	L1	1	
EA13	M1	1	
EA12	M2	0/7	External address (word address)
EA11	M6		
EA10	N4	1	
EA9	N1	1	
EA8	N2	1	
EA7	N6	1	
EA6	P4	1	
EA5	P3	1	
EA4	P2	1	
EA3	P1	1	
EA2	P6		



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions (Continued)			
SIGNAL		TYPET	DESCRIPTION
NAME	NO.	ITPET	DESCRIPTION
			EMIF – DATA
ED31	U18		
ED30	U20		
ED29	T15		
ED28	V18		
ED27	V17		
ED26	V16		
ED25	T12		
ED24	W17		
ED23	T13		
ED22	Y17		
ED21	T11		
ED20	Y16		
ED19	W15		
ED18	V14		
ED17	Y15		
ED16	R9	1/0/7	External data
ED15	Y14	1/0/2	
ED14	V13		
ED13	AA13		
ED12	T10		
ED11	Y13		
ED10	W12		
ED9	Y12		
ED8	Y11		
ED7	V10		
ED6	AA10		
ED5	Y10		
ED4	W10		
ED3	Y9		
ED2	AA9		
ED1	Y8		
ED0	W9		
			EMIF – ASYNCHRONOUS MEMORY CONTROL
ARE	R7	O/Z	Asynchronous memory read enable
AOE	Τ7	O/Z	Asynchronous memory output enable
AWE	V5	O/Z	Asynchronous memory write enable
ARDY	R4	I	Asynchronous memory ready input



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions (Continued)							
SIGNAL			DESCRIPTION				
NAME	NO.	TYPET	DESCRIPTION				
	EMIF – SYNCHRONOUS BURST SRAM CONTROL						
SSADS	V8	O/Z	SBSRAM address strobe				
SSOE	W7	O/Z	SBSRAM output enable				
SSWE	Y7	O/Z	SBSRAM write enable				
SSCLK	AA8	O/Z	SBSRAM clock				
			EMIF – SYNCHRONOUS DRAM CONTROL				
SDA10	V7	O/Z	SDRAM address 10 (separate for deactivate command)				
SDRAS	V6	O/Z	SDRAM row address strobe				
SDCAS	W5	O/Z	SDRAM column address strobe				
SDWE	Т8	O/Z	SDRAM write enable				
SDCLK	Т9	O/Z	SDRAM clock				
		-	EMIF – BUS ARBITRATION				
HOLD	R6	I	Hold request from the host				
HOLDA	B15	0	Hold request acknowledge to the host				
			TIMERS				
TOUT1	G2	O/Z	Timer 1 or general-purpose output				
TINP1	K3	I	Timer 1 or general-purpose input				
TOUT0	M18	O/Z	Timer 0 or general-purpose output				
TINP0	J18	I	Timer 0 or general-purpose input				
			DMA ACTION COMPLETE				
DMAC3	E18						
DMAC2	F19		DMA action complete				
DMAC1	E20] ~	Divid action complete				
DMAC0	G16						
			MULTICHANNEL BUFFERED SERIAL PORT 1 (McBSP1)				
CLKS1	F4	I	External clock source (as opposed to internal)				
CLKR1	H4	I/O/Z	Receive clock				
CLKX1	J4	I/O/Z	Transmit clock				
DR1	E2	I	Receive data				
DX1	G4	O/Z	Transmit data				
FSR1	F3	I/O/Z	Receive frame sync				
FSX1	F2	I/O/Z	Transmit frame sync				



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

	Signal Descriptions (Continued)					
SIGNA NAME	NO.	TYPE [†]	DESCRIPTION			
	MULTICHANNEL BUFFERED SERIAL PORT 0 (McBSP0)					
CLKS0	K18	I	External clock source (as opposed to internal)			
CLKR0	L21	I/O/Z	Receive clock			
CLKX0	K20	I/O/Z	Transmit clock			
DR0	J21	I	Receive data			
DX0	M21	O/Z	Transmit data			
FSR0	P16	I/O/Z	Receive frame sync			
FSX0	N16	I/O/Z	Transmit frame sync			
			RESERVED FOR TEST			
RSV0	N21	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
RSV1	K16	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
RSV2	B13	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
RSV3	B14	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
RSV4	F13	I	Reserved for testing, <i>pull-down</i> with a dedicated 20-k Ω resistor			
RSV5	C15	0	Reserved (leave unconnected, <i>do not</i> connect to power or ground)			
RSV6	F7	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
RSV7	D7	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
RSV8	B5	I	Reserved for testing, pull-up with a dedicated 20-k Ω resistor			
			SUPPLY VOLTAGE PINS			
	C14					
	C8					
	E19					
	E3					
	H11					
	H13					
	H9					
	J10					
	J12					
	J14					
DVDD	J19	S	3.3-V supply voltage			
	J3					
	J8					
	K11					
	K13					
	K15					
	K7					
	K9	1				
	L10	4				
	L12	4				
	L14					



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

Signal Descriptions (Continued)				
SIGNAL	-	TYPET	DESCRIPTION	
NAME	NO.			
			SUPPLY VOLTAGE PINS (CONTINUED)	
	L8			
	IVI I I			
	IVI 13			
	M7			
	MQ	1		
	N10			
	N12			
	N14			
DVnn	N19	S	3.3-V supply voltage	
	N3			
	N8			
	P11			
	P13			
	P9			
	U19			
	U3			
	W14			
	W8			
	A12			
	A13			
	B10			
	B12			
	B6			
	D15			
	D16			
	F10			
	F14			
CVDD	F8	S	2.5-V supply voltage for 'C6201	
	G13		1.0- v supply voltage for Gozo TD	
	G/			
	Go K1			
	M3			
	M4			
	A3			
	A5			
	A7			
	A16			



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

Signal Descriptions (Continued)					
SIGNAL	-	TYPET	DESCRIPTION		
NAME	NO.				
	4.4.0		SUPPLY VOLTAGE PINS (CONTINUED)		
	A18				
	AA0				
	AA15				
	AA17 AA19				
	B2				
	B2 B4				
	B19				
	C1				
	C3				
	C20				
	D2				
	D21	-			
	E1				
	E6				
CVDD	E8	e	2.5-V supply voltage for 'C6201		
CADD	E10	5	1.8-V supply voltage for 'C6201B		
	E12				
	E14				
	E16				
	F5				
	F17				
	F21				
	G1				
	H5				
	H17				
	K5				
	K17				
	CIVI M17				
	P5				
	P17	1			
	R21				
$\dagger I = Input, O = O$	utput, Z =	L High Impe	∎ edance, S = Supply Voltage, GND = Ground		



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

Signal Descriptions (Continued)							
SIGNAL	-	TYPET	DESCRIPTION				
NAME	NO.						
	SUPPLY VOLIAGE PINS (CONTINUED)						
CVDD	T5 T17 U6 U8 U10 U12 U14 U16 U21 V1 V20 W19 W21 Y3 Y18 Y20 AA11 AA12 F20 G18 H16 H18 L19 L20 N20 P18 P19 R10 R14 U4 V11 V12 V15 W13	S	2.5-V supply voltage for 'C6201 1.8-V supply voltage for 'C6201B				



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions (Continued)					
SIGNAL DESCRIPTION					
NAME NO.					
GROUND PINS					
H12					
H14					
H8					
J11					
J13					
J7					
- PL					
К8					
L7					
L9					
M8					
<u>N7</u>					
V _{SS} R3 GND Ground pins					
A17					
A19					
AA3					
AA5					
AA7					
AA14					
AA16					
AA18					
B3					
B18					
B20					



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

Signal Descriptions (Continued)						
SIGNA	_	TYPET	DESCRIPTION			
NAME	NO.					
	Daa		GROUND PINS (CONTINUED)			
	D20	{				
	E5	{				
		{				
	E3	{				
	E13	1				
	E15	1				
	E17	1				
	E21	1				
	F1	1				
	G5	1				
	G17					
	G21	GND				
	H1					
	J5					
	J17					
	L5					
VSS	L17		Ground pins			
	N17					
	P21					
	R1					
	R5					
	R17					
	T21					
	U1					
	U5					
	U7					
	U9					
	U11	{				
	013	{				
	1117	{				
	V2					
	V21	1				
+						



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

Signal Descriptions (Continued)				
SIGNA	SIGNAL		DESCRIPTION	
NAME	NO.			
	W/1			
	W3			
	W20	1		
	Y2			
	Y4	1		
	Y19	1		
	F18	1		
	G19	1		
	H15]		
	J15			
	J16			
	K10			
	K12	GND		
	K14			
	L11			
	L13			
	L15			
VSS	M10		Ground pins	
	M12			
	M14			
	N11			
	N13			
	N15			
	R10			
	P12	1		
	P14	1		
	P15			
	P7	1		
	P8			
	R19			
	T4	1		
	W11	1		
	W16	1		
	W6	1		
†I = Input, O = C	Output, Z =	High Impe	edance, S = Supply Voltage, GND = Ground	





SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

	Signal Descriptions (Continued)									
SIGNA	SIGNAL NAME NO.		DESCRIPTION							
NAME	NO.	ITPET	DESCRIPTION							
			REMAINING UNCONNECTED PINS							
	D13									
	D14									
	D18									
	D3									
	D6									
	F12									
	F16									
	G12									
	G15									
NC	H19		Unconnected pins							
	H20									
	H21									
	L16									
	M16									
	M19									
	V19									
	V4									
	W18									
	W4									



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



functional block diagram



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

signal groups







SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



Figure 2. Peripheral Signals



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

CPU description

The CPU fetches VelociTI advanced very-long instruction words (VLIW) (256 bits wide) to supply up to eight 32-bit instructions to the eight functional units during every clock cycle. The VelociTI VLIW architecture features controls by which all eight units do not have to be supplied with instructions if they are not ready to execute. The first bit of every 32-bit instruction determines if the next instruction belongs to the same execute packet as the previous instruction, or whether it should be executed in the following clock as a part of the next execute packet. Fetch packets are always 256 bits wide; however, the execute packets can vary in size. The variable-length execute packets are a key memory-saving feature, distinguishing the 'C6200[†] CPU from other VLIW architectures.

The CPU features two sets of functional units. Each set contains four units and a register file. One set contains functional units .L1, .S1, .M1, and .D1; the other set contains units .D2, .M2, .S2, and .L2. The two register files each contain 16 32-bit registers for a total of 32 general-purpose registers. The two sets of functional units, along with two register files, compose sides A and B of the CPU (see Figure 3 and Figure 4). The four functional units on each side of the CPU can freely share the 16 registers belonging to that side. Additionally, each side features a single data bus connected to all the registers on the other side, by which the two sets of functional units can access data from the register files on the opposite side. While register access by functional units on the same side of the CPU as the register file can service all the units in a single clock cycle, register access using the register file across the CPU supports one read and one write per cycle.

Another key feature of the 'C6200 CPU is the load/store architecture, where all instructions operate on registers (as opposed to data in memory). Two sets of data-addressing units (.D1 and .D2) are responsible for all data transfers between the register files and the memory. The data address driven by the .D units allows data addresses generated from one register file to be used to load or store data to or from the other register file. The 'C6200 CPU supports a variety of indirect addressing modes using either linear- or circular-addressing modes with 5- or 15-bit offsets. All instructions are conditional, and most can access any one of the 32 registers. Some registers, however, are singled out to support specific addressing or to hold the condition for conditional instructions (if the condition is not automatically "true"). The two .M functional units are dedicated for multiplies. The two .S and .L functional units perform a general set of arithmetic, logical, and branch functions with results available every clock cycle.

The processing flow begins when a 256-bit-wide instruction fetch packet is fetched from a program memory. The 32-bit instructions destined for the individual functional units are "linked" together by "1" bits in the least significant bit (LSB) position of the instructions. The instructions that are "chained" together for simultaneous execution (up to eight in total) compose an execute packet. A "0" in the LSB of an instruction breaks the chain, effectively placing the instructions that follow it in the next execute packet. If an execute packet crosses the fetch packet boundary (256 bits wide), the assembler places it in the next fetch packet, while the remainder of the current fetch packet is padded with NOP instructions. The number of execute packets within a fetch packet can vary from one to eight. Execute packets are dispatched to their respective functional units at the rate of one per clock cycle and the next 256-bit fetch packet is not fetched until all the execute packets from the current fetch packet have been dispatched. After decoding, the instructions simultaneously drive all active functional units for a maximum execution rate of eight instructions every clock cycle. While most results are stored in 32-bit registers, they can be subsequently moved to memory as bytes or half-words as well. All load and store instructions are byte-, half-word, or word-addressable.

[†] Where unique device characteristics are specified, SM320C6201 and SMJ320C6201B identifiers are used. For generic characteristics, no identifiers are needed, 'C62xx is used, or 'C6200 is used.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

CPU description (continued)



Figure 3. SM320C6200 CPU Block Diagram



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

CPU description (continued)







SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

clock PLL

All of the 'C62xx clocks are generated from a single source through the CLKIN pin. This source clock either drives the PLL, which generates the internal CPU clock, or bypasses the PLL to become the CPU clock.

To use the PLL to generate the CPU clock, the filter circuit shown in Figure 5 must be properly designed. Note that for 'C6201, the EMI filter must be powered by the core voltage (2.5 V), and for 'C6201B, it must be powered by the I/O voltage (3.3 V).

To configure the 'C62xx PLL clock for proper operation, see Figure 5 and Table 1. To minimize the clock jitter, a single clean power supply should power both the 'C62x device and the external clock oscillator circuit. The minimum CLKIN rise and fall times should also be observed. See the *input and output clocks* section for input clock timing requirements.



- NOTES: A. For the 'C6201 CLKMODE x4, values for C1, C2, and R1 depend on CLKIN and CLKOUT frequencies.
 - For the 'C6201B CLKMODE x4, values for C1, C2, and R1 are fixed and apply to all valid frequency ranges of CLKIN and CLKOUT.
 B. For CLKMODE x1, the PLL is bypassed and all six external PLL components can be removed. For this case, the PLLV terminal has to be connected to a clean supply and the PLLG and PLLF terminals should be tied together.
 - C. Due to overlap of frequency ranges when choosing the PLLFREQ, more than one frequency range can contain the CLKOUT1 frequency. Choose the lowest frequency range that includes the desired frequency. For example, CLKOUT1 = 133 MHz, a PLLFREQ value of 000b should be used for both the 'C6201 and the 'C6201B. For CLKOUT1 = 200 MHz, PLLFREQ should be set to 010b for the 'C6201 or 001b for the 'C6201B. PLLFREQ values other than 000b, 001b, and 010b are reserved.
 - D. EMI filter manufacturer TDK part number ACF451832-153-T
 - E. For the 'C6201B, the 3.3-V supply for the EMI filter (and PLLV) must be from the same 3.3-V power plane supplying the I/O voltage, DVDD.

Figure 5. PLL Block Diagram



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

clock PLL (continued)

CYCLE TIME (ns)	CLKMODE	CLKIN (MHz)	CLKOUT1 (MHz)	R1 (Ω)	C1 (μF)	C2 (pF)	EMI FILTER PART NO.‡	TYPICAL LOCK TIME (μs)§
5	x4	50	200	16.9	0.15	2700	TDK #153	59
5.5	x4	45.5	181.8	13.7	0.18	3900	TDK #153	49
6	x4	41.6	166.7	17.4	0.15	3300	TDK #153	68
6.5	x4	38.5	153.8	16.2	0.18	3900	TDK #153	70
7	x4	35.7	142.9	15	0.22	3900	TDK #153	72
7.5	x4	33.3	133.3	16.2	0.22	3900	TDK #153	84
8	x4	31.3	125	14	0.27	4700	TDK #153	77
8.5	x4	29.4	117.7	11.8	0.33	6800	TDK #153	67
9	x4	27.7	111.1	11	0.39	6800	TDK #153	68
9.5	x4	26.3	105.3	10.5	0.39	8200	TDK #153	65
10	x4	25	100	10	0.47	8200	TDK #153	68

Table 1. SM320C6201 PLL Component Selection Table[†]

[†] For CLKMODE x1, the PLL is bypassed and all six external PLL components can be removed. For this case, the PLLV terminal has to be connected to a clean supply and the PLLG and PLLF terminals should be tied together.

[‡] Full EMI filter part number : ACF 451832-153-T

§ Under some operating conditions, the maximum PLL lock time may vary as much as 150% from the specified typical value. For example, if the typical lock time is specified as 100 μs, the maximum value may be as long as 250 μs.

Table 2. SM320C6201B PLL Component Selection Table[†]

CLKMODE	R1	C1	C2	EMI FILTER	TYPICAL
	(Ω)	(nF)	(pF)	PART NO.‡	LOCK TIME (μs)§
x4	60.4	27	560	TDK #153	75

[†] For CLKMODE x1, the PLL is bypassed and all six external PLL components can be removed. For this case, the PLLV terminal has to be connected to a clean supply and the PLLG and PLLF terminals should be tied together.

[‡]Full EMI filter part number : ACF 451832-153-T

§ Under some operating conditions, the maximum PLL lock time may vary as much as 150% from the specified typical value. For example, if the typical lock time is specified as 100 μs, the maximum value may be as long as 250 μs.

power supply sequencing

For the 'C6201 device, the 2.5-V supply powers the core and the 3.3-V supply powers the I/O buffers. For the 'C6201B device, the 1.8-V supply powers the core and the 3.3-V supply powers the I/O buffers. The core supply should be powered up first, or at the same time as the I/O buffers. This is to ensure that the I/O buffers have valid inputs from the core before the output buffers are powered up, thus preventing bus contention with other chips on the board.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

development support

Texas Instruments (TI[™]) offers an extensive line of development tools for the 'C6200 generation of DSPs, including tools to evaluate the performance of the processors, generate code, develop algorithm implementations, and fully integrate and debug software and hardware modules.

The following products support development of 'C6200-based applications:

Software Development Tools:

Assembly optimizer Assembler/Linker Simulator Optimizing ANSI C compiler Application algorithms C/Assembly debugger and code profiler

Hardware Development Tools:

Extended development system (XDS[™]) emulator (supports 'C6200 multiprocessor system debug) EVM (Evaluation Module)

The *TMS320 DSP Development Support Reference Guide* (SPRU011) contains information about development-support products for all TMS320 family member devices, including documentation. See this document for further information on TMS320 documentation or any TMS320 support products from Texas Instruments. An additional document, the *TMS320 Third-Party Support Reference Guide* (SPRU052), contains information about TMS320-related products from other companies in the industry. To receive TMS320 literature, contact the Literature Response Center at 800/477-8924.

See Table 3 for a complete listing of development-support tools for the 'C6200. For information on pricing and availability, contact the nearest TI field sales office or authorized distributor.

DEVELOPMENT TOOL	PLATFORM	PART NUMBER						
	Software							
C Compiler/Assembler/Linker/Assembly Optimizer	Win32™	TMDX3246855-07						
C Compiler/Assembler/Linker/Assembly Optimizer	SPARC [™] Solaris [™]	TMDX324655-07						
Simulator	Win32	TMDS3246851-07						
Simulator	SPARC Solaris	TMDS3246551-07						
XDS510 [™] Debugger/Emulation Software	Win32, Windows NT™	TMDX324016X-07						
	Hardware							
XDS510 Emulator [†]	PC	TMDS00510						
XDS510WS™ Emulator‡	SCSI	TMDS00510WS						
Software/Hardware								
EVM Evaluation Kit	PC/Win95/Windows NT	TMDX3260A6201						
EVM Evaluation Kit (including TMDX3246855–07)	PC/Win95/Windows NT	TMDX326006201						

Table 3. TMS320C6xx Development-Support Tools

[†] Includes XDS510 board and JTAG emulation cable. TMDX324016X-07 C-source Debugger/Emulation software is not included. [‡] Includes XDS510WS box, SCSI cable, power supply, and JTAG emulation cable.

TI, XDS, XDS510, and XDS510WS are trademarks of Texas Instruments Incorporated. Win32 and Windows NT are trademarks of Microsoft Corporation.

SPARC is a trademark of SPARC International, Inc. Solaris is a trademark of Sun Microsystems, Inc.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

device and development-support tool nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all TMS320 devices and support tools. Each TMS320 member has one of three prefixes: TMX, TMP, or TMS. Texas Instruments recommends two of three possible prefix designators for support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (TMX/TMDX) through fully qualified production devices/tools (TMS/TMDS). This development flow follows.

Device development evolutionary flow:

- **TMX** Experimental device that is not necessarily representative of the final device's electrical specifications
- **TMP** Final silicon die that conforms to the device's electrical specifications but has not completed quality and reliability verification
- TMS Fully qualified production device
- **SMX** Experimental device that is not necessarily representative of the final device's electrical specifications, 25°C tested, military/industrial ceramic dimpled Ball Grid Array package
- **SM** Fully TI-qualified production device; offered in extended temperature ranges: -40°C to +90°C (A range), -55°C to +105°C (S range), and -55°C to +125°C (M range); in ceramic dimpled BGA package
- **SMJ** Fully SMD-qualified production device, -55°C to +125°C temperature range, in the ceramic dimpled Ball Grid Array package

Support tool development evolutionary flow:

- **TMDX** Development-support product that has not yet completed Texas Instruments internal qualification testing.
- TMDS Fully qualified development-support product

TMX and TMP devices and TMDX development-support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

TMS devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. TI's standard warranty applies.

Predictions show that prototype devices (TMX or TMP) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (for example, GGP, GJC, or GJL) and the device speed range in megahertz (for example, -200 is 200 MHz). Figure 6 provides a legend for reading the complete device name for any TMS320 family member.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999



- CC = Chip Carrier
- QFP = Quad Flat Package
- TQFP = Thin Quad Flat Package
- BGA = Ball Grid Array

Figure 6. TMS320 Device Nomenclature (Including SM320C6201/SMJ320C6201B)



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

documentation support

Extensive documentation supports all TMS320 family generations of devices from product announcement through applications development. The types of documentation available include: data sheets, such as this document, with design specifications; complete user's reference guides for all devices; technical briefs; development-support tools; and hardware and software applications. The following is a brief, descriptive list of support documentation specific to the 'C6x devices:

The *TMS320C62x/C67x CPU and Instruction Set Reference Guide* (literature number SPRU189) describes the 'C62x/C67x CPU architecture, instruction set, pipeline, and associated interrupts.

The *TMS320C6201/C6701 Peripherals Reference Guide* (literature number SPRU190) describes functionally the peripherals available on 'C6x devices, such as the external memory interface (EMIF), host-port interface (HPI), multichannel buffered serial ports (McBSPs), direct-memory-access (DMA) controller, clocking and phase-locked loop (PLL); and power-down modes. This guide also includes information on internal data and program memories.

The *TMS320C62x/C67x Programmer's Guide* (literature number SPRU198) describes ways to optimize C and assembly code for 'C6x devices and includes application program examples.

The *TMS320C6x Optimizing C Compiler User's Guide* (literature number SPRU187) describes the 'C6x C compiler and the assembly optimizer, explaining that the C compiler accepts ANSI standard C source code, and produces assembly language source code for the 'C6x generation devices, and that the assembly optimizer helps to optimize the programmer's assembly code.

The *TMS320C6x C Source Debugger User's Guide* (literature number SPRU188) describes how to invoke the 'C6x simulator and emulator versions of the C source debugger interface and discusses various aspects of the debugger, including: command entry, code execution, data management, breakpoints, profiling, and analysis.

The *TMS320C6x Peripheral Support Library Programmer's Reference* (literature number SPRU273) describes the contents of the 'C6x peripheral support library of functions and macros. It lists functions and macros both by header file and alphabetically, provides a complete description of each, and gives code examples to show how they are used.

The *TMS320C6x Evaluation Module Reference Guide* (literature number SPRU269) provides instructions for installing and operating the 'C6x evaluation module. It also includes support software documentation, application programming interfaces, and technical reference material.

The *TMS320C62x/C67x Technical Brief* (literature number SPRU197) gives an introduction to the 'C62x/C67x devices, associated development tools, and third-party support.

A series of DSP textbooks is published by Prentice-Hall and John Wiley & Sons to support DSP research and education. The TMS320 newsletter, *Details on Signal Processing*, is published quarterly and distributed to update TMS320 customers on product information. The TMS320 DSP bulletin board service (BBS) provides access to information pertaining to the TMS320 family, including documentation, source code, and object code for many DSP algorithms and utilities. The BBS can be reached at 281/274-2323.

Information regarding TI DSP products is also available on the Worldwide Web at http://www.ti.com uniform resource locator (URL).



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

absolute maximum ratings over operating case temperature range (unless otherwise noted)[†]

Supply voltage range, CV _{DD} (see Note 1) for 'C6201 .	–0.3 V to 3 V
Supply voltage range, CV _{DD} (see Note 1) for 'C6201B	
Supply voltage range, DV _{DD} (see Note 1)	-0.3 V to 4 V
Input voltage range	–0.3 V to 4 V
Output voltage range	–0.3 V to 4 V
Operating case temperature range, T _C (S temperature)	
(M temperature)–55°C to 125°C
Storage temperature range, T _{stg}	–55°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to V_{SS}.

recommended operating conditions

		'C6201			'C6201B		LINUT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
CVDD	Supply voltage	2.38	2.50	2.62	1.71	1.8	1.89	V
DVDD	Supply voltage	3.14	3.30	3.46	3.14	3.30	3.46	V
V _{SS}	Supply ground	0	0	0	0	0	0	V
VIH	High-level input voltage	2.0			2.0	2		V
VIL	Low-level input voltage			0.8		5	0.8	V
ЮН	High-level output current			-12	-12		mA	
IOL	Low-level output current			12	2		12	mA
ТС	Operating case temperature	-55		105	-55		125	°C



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

electrical characteristics over recommended ranges of supply voltage and operating case temperature (unless otherwise noted)

	DADAMETED	TEST CONDITIONS		'C6201		'	C6201B		UNIT
	FARAMETER	TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
VOH	High-level output voltage	DV _{DD} = MIN, I _{OH} = MAX	2.4			2.4			V
VOL	Low-level output voltage	$DV_{DD} = MIN,$ $I_{OL} = MAX$			0.6			0.6	V
Ц	Input current [†]	$V_I = V_{SS}$ to DV_{DD}			±10		N.	±10	uA
IOZ	Off-state output current	$V_{O} = DV_{DD} \text{ or } 0 V$			±10		P	±10	uA
IDD2V	Supply current, CPU + CPU memory access [‡]	CV _{DD} = NOM, CPU clock = 167 MHz		1860			780		mA
I _{DD2V}	Supply current, peripherals§	CV _{DD} = NOM, CPU clock = 167 MHz		200		04d	140		mA
IDD3V	Supply current, I/O pins $ m I$	DV _{DD} = NOM, CPU clock = 167 MHz		100			100		mA
Ci	Input capacitance				10			10	pF
Co	Output capacitance				10			10	pF

[†] TMS and TDI are not included due to internal pullups.

TRST is not included due to internal pulldown.

[‡] Measured with average CPU activity:

50% of time: 8 instructions per cycle, 32-bit DMEM access per cycle

50% of time: 2 instructions per cycle, 16-bit DMEM access per cycle

§ Measured with average peripheral activity: 50% of time: Timers at max rate

McBSPs at E1 rate

DMA burst transfer between DMEM and SDRAM

50% of time: Timers at max rate

McBSPs at E1 rate

DMA servicing McBSPs

 \P Measured with average I/O activity (30-pF load, SDCLK on):

25% of time: Reads from external SDRAM

- 25% of time: Writes to external SDRAM
- 50% of time: No activity

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999



PARAMETER MEASUREMENT INFORMATION

[†] Typical distributed load circuit capacitance

Figure 7. TTL-Level Outputs

signal transition levels

All input and output timing parameters are referenced to 1.5 V for both "0" and "1" logic levels.



Figure 8. Input and Output Voltage Reference Levels for AC Timing Measurements



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

INPUT AND OUTPUT CLOCKS

timing requirements for CLKIN[†] (see Figure 9) ('C6201)

				'C620	1-150		
NO.			CLKN = X	IODE k4	CLKN = X	IODE k1	UNIT
			MIN	MAX	MIN	MAX	
1	^t c(CLKIN)	Cycle time, CLKIN	24*		6.67		ns
2	^t w(CLKINH)	Pulse duration, CLKIN high	9.8*		2.7*		ns
3	^t w(CLKINL)	Pulse duration, CLKIN low	9.8*		2.7*		ns
4	^t t(CLKIN)	Transition time, CLKIN		5*		0.6*	ns

[†] The reference points for the rise and fall transitions are measured at 20% and 80%, respectively, of V_{IH}.

*This parameter is not production tested.

timing requirements for CLKIN (see Figure 9) ('C6201B)

				'C6201	B-150			'C6201	B-200		
NO.			CLKN =	CLKMODE CLKMODE = x4 = x1		CLKMODE = x4		CLKMODE = x1		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
1	^t c(CLKIN)	Cycle time, CLKIN	24	EW	6.67	EW	20	IEW	5	^{IEW}	ns
2	^t w(CLKINH)	Pulse duration, CLKIN high	9.8	PEL	2.7	PRE	8	24	2.25	14	ns
3	^t w(CLKINL)	Pulse duration, CLKIN low	9.8		2.7	,	8		2.25		ns
4	tt(CLKIN)	Transition time, CLKIN	PRO	5	44	0.6	PH 0	5	PHO DE	0.6	ns



Figure 9. CLKIN Timings

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

INPUT AND OUTPUT CLOCKS (CONTINUED)

switching characteristics for CLKOUT1^{†‡} (see Figure 10) ('C6201)

				²C6201-150						
NO.	D. PARAMETER		CLKMO	DE = x4	CLKMO	UNIT				
			MIN	MAX	MIN	MAX				
1	^t c(CKO1)	Cycle time, CLKOUT1	P – 0.7*	P + 0.7*	P – 0.7*	P + 0.7*	ns			
2	^t w(CKO1H)	Pulse duration, CLKOUT1 high	(P/2) - 0.5*	(P/2)+0.5*	PH – 0.5*	PH + 0.5*	ns			
3	^t w(CKO1L)	Pulse duration, CLKOUT1 low	(P/2) - 0.5*	(P/2)+0.5*	PL – 0.5*	PL + 0.5*	ns			
4	^t t(CKO1)	Transition time, CLKOUT1		0.6*		0.6*	ns			

[†] PH is the high period of CLKOUT1 in ns and PL is the low period of CLKOUT1 in ns.

 $\ddagger P = 1/CPU$ clock frequency in nanoseconds (ns).

*This parameter is not production tested.

switching characteristics for CLKOUT1^{†‡} (see Figure 10) ('C6201B)

NO.							
		PARAMETER	CLKMO	DE = x4	CLKMO	UNIT	
			MIN	MAX	MIN	MAX	
1	^t c(CKO1)	Cycle time, CLKOUT1	P – 0.7	P + 0.7	P – 0.7	P + 0.7	ns
2	^t w(CKO1H)	Pulse duration, CLKOUT1 high	(P/2) - 0.5	(P/2) + 0.5	PH - 0.5	PH + 0.5	ns
3	^t w(CKO1L)	Pulse duration, CLKOUT1 low	(P/2) – 0.5	(P/2) + 0.5	PL – 0.5	PL + 0.5	ns
4	^t t(CKO1)	Transition time, CLKOUT1	240 10	0.6	D ⁴ d	ک 0.6	ns

[†] PH is the high period of CLKOUT1 in ns and PL is the low period of CLKOUT1 in ns.

 $\ddagger P = 1/CPU$ clock frequency in nanoseconds (ns).



Figure 10. CLKOUT1 Timings



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

INPUT AND OUTPUT CLOCKS (CONTINUED)

switching characteristics for CLKOUT2[†] (see Figure 11)

NO.		PARAMETER	'C620 [,]	1-150	'C6201E 'C6201E	UNIT	
			MIN	MAX	MIN	MAX	
1	^t c(CKO2)	Cycle time, CLKOUT2	2P – 0.7*	2P + 0.7*	2P – 0.7	2P + 0.7	ns
2	^t w(CKO2H)	Pulse duration, CLKOUT2 high	P – 0.7*	P + 0.7*	P - 0.7	P + 0.7	ns
3	^t w(CKO2L)	Pulse duration, CLKOUT2 low	P – 0.7*	P + 0.7*	P – 0.7	P + 0.7	ns
4	^t t(CKO2)	Transition time, CLKOUT2		0.6*	044	0.6	ns

 $^{\dagger}P = 1/CPU$ clock frequency in ns.

*This parameter is not production tested.



Figure 11. CLKOUT2 Timings

SDCLK, SSCLK timing parameters

SDCLK timing parameters are the same as CLKOUT2 parameters.

SSCLK timing parameters are the same as CLKOUT1 or CLKOUT2 parameters, depending on SSCLK configuration.

switching characteristics for the relation of SSCLK, SDCLK, and CLKOUT2 to CLKOUT1 (see Figure 12)^{\dagger}

NO.	PARAMETER		'C620	1-150	'C6201 'C6201	UNIT	
				MAX	MIN	MAX	
1	^t d(CKO1-SSCLK)	Delay time, CLKOUT1 edge to SSCLK edge	-1.2*	1.6*	(P/2) + 0.2	(P/2) + 4.2	ns
2	^t d(CKO1-SSCLK1/2)	Delay time, CLKOUT1 edge to SSCLK edge (1/2 clock rate)	-1.0*	2.4*	(P/2) – 1	(P/2) + 2.4	ns
3	td(CKO1-CKO2)	Delay time, CLKOUT1 edge to CLKOUT2 edge	-1.0*	2.4*	(P/2) – 1	(P/2) + 2.4	ns
4	td(CKO1-SDCLK)	Delay time, CLKOUT1 edge to SDCLK edge	-1.0*	2.4*	(P/2) – 1	(P/2) + 2.4	ns

 $^{\dagger}P = 1/CPU$ clock frequency in ns.

*This parameter is not production tested.

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



Figure 12. Relation of CLKOUT2, SDCLK, and SSCLK to CLKOUT1



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

ASYNCHRONOUS MEMORY TIMING

timing requirements for asynchronous memory cycles[†] (see Figure 13 and Figure 14)

NO.			'C6201-150		'C6201B-150		'C6201B-200		
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
6	^t su(EDV-CKO1H)	Setup time, read EDx valid before CLKOUT1 high	5.0		5.0		4.0		ns
7	^t h(CKO1H-EDV)	Hold time, read EDx valid after CLKOUT1 high	0		0	Miller.	0.8	MEM.	ns
10	t _{su} (ARDY-CKO1H)	Setup time, ARDY valid before CLKOUT1 high	5.0*		5.0		4.0		ns
11	^t h(CKO1H-ARDY)	Hold time, ARDY valid after CLKOUT1 high	0*		200		0.8		ns

[†] To ensure data setup time, simply program the strobe width wide enough. ARDY is internally synchronized. If ARDY does meet setup or hold time, it may be recognized in the current cycle or the next cycle. Thus, ARDY can be an asynchronous input.

*This parameter is not production tested.

switching characteristics for asynchronous memory cycles[‡] (see Figure 13 and Figure 14)

NO	PARAMETER		'C6201-150		'C6201B-150		'C6201B-200		LINUT
NO.			MIN	MAX	MIN	MAX	MIN	MAX	
1	^t d(CKO1H-CEV)	Delay time, CLKOUT1 high to CEx valid	-1.0	5.0	-1.0	5.0	-0.2	4.0	ns
2	^t d(CKO1H-BEV)	Delay time, CLKOUT1 high to BEx valid	-1.0	5.0	-1.0	5.0	-0.2	4.0	ns
3	^t d(CKO1H-BEIV)	Delay time, CLKOUT1 high to BEx invalid	-1.0*	5.0*	-1.0	5.0	-0.2	4.0	ns
4	^t d(CKO1H-EAV)	Delay time, CLKOUT1 high to EAx valid	-1.0	5.0	-1.0	5.0	-0.2	4.0	ns
5	^t d(CKO1H-EAIV)	Delay time, CLKOUT1 high to EAx invalid	-1.0*	5.0*	-1.0	5.0	-0.2	4.0	ns
8	^t d(CKO1H-AOEV)	Delay time, CLKOUT1 high to AOE valid	-1.0	5.0	-1.0	5.0	-0.2	4.0	ns
9	^t d(CKO1H-AREV)	Delay time, CLKOUT1 high to ARE valid	-1.0	5.0	-1.0	5.0	-0.2	4.0	ns
12	^t d(CKO1H-EDV)	Delay time, CLKOUT1 high to EDx valid		5.0	20	5.0	ю _қ	4.0	ns
13	^t d(CKO1H-EDIV)	Delay time, CLKOUT1 high to EDx invalid	-1.0*		Q -1.0		0.2		ns
14	td(CKO1H-AWEV)	Delay time, CLKOUT1 high to AWE valid	-1.0	5.0	-1.0	5.0	-0.2	4.0	ns

[‡] The minimum delay is also the minimum output hold after CLKOUT1 high.

*This parameter is not production tested.

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



ASYNCHRONOUS MEMORY TIMING (CONTINUED)

Figure 13. Asynchronous Memory Read Timing



Figure 14. Asynchronous Memory Write Timing



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

SYNCHRONOUS-BURST MEMORY TIMING

timing requirements for synchronous-burst SRAM cycles (full-rate SSCLK) (see Figure 15)

NO.			'C6201-150		'C6201B-150 'C6201B-200		UNIT
			MIN	MAX	MIN	MAX	
7	t _{su} (EDV-SSCLKH)	Setup time, read EDx valid before SSCLK high	1.5		1.5	JIE.	ns
8	^t h(SSCLKH-EDV)	Hold time, read EDx valid after SSCLK high	1.2		1.5		ns

switching characteristics for synchronous-burst SRAM cycles[†] (full-rate SSCLK) (see Figure 15 and Figure 16)

NO.	PARAMETER		'C6201	-150	'C6201B-150 'C6201B-200	UNIT
				MAX	MIN MAX	
1	tsu(CEV-SSCLKH)	Setup time, CEx valid before SSCLK high	P – 4.7		0.5P – 1.3	ns
2	toh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	0		0.5P – 2.3 🔊	ns
3	tsu(BEV-SSCLKH)	Setup time, BEx valid before SSCLK high	P – 4.7		0.5P – 1.3 🛛 🖉	ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	1*		0.5P – 2.3 🔊	ns
5	tsu(EAV-SSCLKH)	Setup time, EAx valid before SSCLK high	P – 5.7		0.5P – 1.3	ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	1*		0.5P – 2.3	ns
9	tsu(ADSV-SSCLKH)	Setup time, SSADS valid before SSCLK high	P – 3.7		0.5P – 1.3	ns
10	toh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	0		0.5P – 2.3	ns
11	t _{su} (OEV-SSCLKH)	Setup time, SSOE valid before SSCLK high	P – 4.7		0.5P – 1.3	ns
12	toh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	0		0.5P – 2.3	ns
13	tsu(EDV-SSCLKH)	Setup time, EDx valid before SSCLK high	P – 4.7		0.5P – 1.3	ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	1*		0.5P – 2.3	ns
15	tsu(WEV-SSCLKH)	Setup time, SSWE valid before SSCLK high	P – 3.7		0.5P – 1.3	ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	0		0.5P – 2.3	ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter or SSCLK duty cycle. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

*This parameter is not production tested.

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.


SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)





Figure 16. SBSRAM Write Timing (Full-Rate SSCLK)



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

timing requirements for synchronous-burst SRAM cycles (half-rate SSCLK) (see Figure 17) ('C6201)

NO			'C6201	-150	UNIT
NO.			MIN	MAX	UNIT
7	^t su(EDV-SSCLKH)	Setup time, read EDx valid before SSCLK high	3.6*		ns
8	^t h(SSCLKH-EDV)	Hold time, read EDx valid after SSCLK high	1.2*		ns

*This parameter is not production tested.

switching characteristics for synchronous-burst SRAM cycles[†] (half-rate SSCLK) (see Figure 17 and Figure 18) ('C6201)

NO.			'C6201-	150	LINIT
NO.		PARAMEIER	MIN	MAX	UNIT
1	^t su(CEV-SSCLKH)	Setup time, CEx valid before SSCLK high	P – 4.1*		ns
2	^t oh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	P – 5.7*		ns
3	^t su(BEV-SSCLKH)	Setup time, BEx valid before SSCLK high	P – 4*		ns
4	^t oh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	P – 5.7*		ns
5	^t su(EAV-SSCLKH)	Setup time, EAx valid before SSCLK high	P – 4*		ns
6	^t oh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	P – 5.7*		ns
9	^t su(ADSV-SSCLKH)	Setup time, SSADS valid before SSCLK high	P – 4*		ns
10	^t oh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	P – 5.7*		ns
11	^t su(OEV-SSCLKH)	Setup time, SSOE valid before SSCLK high	P – 4*		ns
12	^t oh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	P – 5.7*		ns
13	^t su(EDV-SSCLKH)	Setup time, EDx valid before SSCLK high	P – 4*		ns
14	^t oh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	P – 5.7*		ns
15	tsu(WEV-SSCLKH)	Setup time, SSWE valid before SSCLK high	P – 4*		ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	P – 5.7*		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter or SSCLK duty cycle. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

*This parameter is not production tested.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

timing requirements for synchronous-burst SRAM cycles (half-rate SSCLK) (see Figure 17) ('C6201B)

			'C6201	B-150	'C6201	B-200	UNIT
NO.			MIN	MAX	MIN	MAX	
7	^t su(EDV-SSCLKH)	Setup time, read EDx valid before SSCLK high	4.2		2.5		ns
8	^t h(SSCLKH-EDV)	Hold time, read EDx valid after SSCLK high	1.5		1.5		ns

switching characteristics for synchronous-burst SRAM cycles[†] (half-rate SSCLK) (see Figure 17 and Figure 18) ('C6201B)

NO			'C6201B-	150	'C6201B·	-200	UNIT
NO.		PARAMETER	MIN	MAX	MIN	MAX	UNIT
1	^t su(CEV-SSCLKH)	Setup time, CEx valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
2	^t oh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns
3	^t su(BEV-SSCLKH)	Setup time, BEx valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns
5	^t su(EAV-SSCLKH)	Setup time, EAx valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns
9	^t su(ADSV-SSCLKH)	Setup time, SSADS valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
10	toh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns
11	t _{su} (OEV-SSCLKH)	Setup time, SSOE valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
12	toh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns
13	tsu(EDV-SSCLKH)	Setup time, EDx valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns
15	t _{su} (WEV-SSCLKH)	Setup time, SSWE valid before SSCLK high	1.5P – 5.5		1.5P – 3		ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	0.5P – 2.4		0.5P – 1.5		ns

PRODUCT PREVIEW

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter or SSCLK duty cycle. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)









SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

SYNCHRONOUS DRAM TIMING

timing requirements for synchronous DRAM cycles (see Figure 19) ('C6201)

		'C620	LINIT		
NO.			MIN	MAX	UNIT
7	tsu(EDV-SDCLKH)	Setup time, read EDx valid before SDCLK high	3.5		ns
8	^t h(SDCLKH-EDV)	Hold time, read EDx valid after SDCLK high	1.2		ns

switching characteristics for synchronous DRAM cycles[†] (see Figure 19–Figure 24) ('C6201)

NO			'C6201	-150	LINIT
NO.		PARAMEIER	MIN	MAX	UNIT
1	tsu(CEV-SDCLKH)	Setup time, CEx valid before SDCLK high	P – 4.2		ns
2	toh(SDCLKH-CEV)	Output hold time, CEx valid after SDCLK high	P – 5.2		ns
3	tsu(BEV-SDCLKH)	Setup time, BEx valid before SDCLK high	P – 4.2		ns
4	toh(SDCLKH-BEIV)	Output hold time, BEx invalid after SDCLK high	P – 5.2*		ns
5	tsu(EAV-SDCLKH)	Setup time, EAx valid before SDCLK high	P – 4.2		ns
6	toh(SDCLKH-EAIV)	Output hold time, EAx invalid after SDCLK high	P – 5.2*		ns
9	tsu(SDCAS-SDCLKH)	Setup time, SDCAS valid before SDCLK high	P – 4.2		ns
10	toh(SDCLKH-SDCAS)	Output hold time, SDCAS valid after SDCLK high	P – 5.2		ns
11	tsu(EDV-SDCLKH)	Setup time, EDx valid before SDCLK high	P – 4.2*		ns
12	toh(SDCLKH-EDIV)	Output hold time, EDx invalid after SDCLK high	P – 5.2*		ns
13	t _{su} (SDWE-SDCLKH)	Setup time, SDWE valid before SDCLK high	P – 4.2		ns
14	toh(SDCLKH-SDWE)	Output hold time, SDWE valid after SDCLK high	P – 5.2		ns
15	tsu(SDA10V-SDCLKH)	Setup time, SDA10 valid before SDCLK high	P – 4.2		ns
16	toh(SDCLKH-SDA10IV)	Output hold time, SDA10 invalid after SDCLK high	P – 5.2*		ns
17	t _{su} (SDRAS-SDCLKH)	Setup time, SDRAS valid before SDCLK high	P – 4.2		ns
18	toh(SDCLKH-SDRAS)	Output hold time, SDRAS valid after SDCLK high	P – 5.2		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter or SDCLK duty cycle. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

*This parameter is not production tested.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

SYNCHRONOUS DRAM TIMING (CONTINUED)

timing requirements for synchronous DRAM cycles (see Figure 19) ('C6201B)

NO		'C6201B	-150 'C620	1B-200	
NO.		MIN	MAX MIN	MAX	UNIT
7	t _{su} (EDV-SDCLKH) Setup time, read EDx valid before SDCLK high	1.5	1		ns
8	th(SDCLKH-EDV) Hold time, read EDx valid after SDCLK high	3	3		ns

switching characteristics for synchronous DRAM cycles[†] (see Figure 19–Figure 24) ('C6201B)

			'C6201B-1	50	'C6201B-200		LINUT
NO.		PARAMETER	MIN	MAX	MIN	MAX	UNIT
1	^t su(CEV-SDCLKH)	Setup time, CEx valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
2	toh(SDCLKH-CEV)	Output hold time, CEx valid after SDCLK high	0.5P – 2		0.5P – 1		ns
3	^t su(BEV-SDCLKH)	Setup time, BEx valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
4	^t oh(SDCLKH-BEIV)	Output hold time, BEx invalid after SDCLK high	0.5P – 2		0.5P – 1		ns
5	^t su(EAV-SDCLKH)	Setup time, EAx valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
6	^t oh(SDCLKH-EAIV)	Output hold time, EAx invalid after SDCLK high	0.5P – 2		0.5P – 1		ns
9	^t su(SDCAS-SDCLKH)	Setup time, SDCAS valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
10	toh(SDCLKH-SDCAS)	Output hold time, SDCAS valid after SDCLK high	0.5P – 2		0.5P – 1		ns
11	^t su(EDV-SDCLKH)	Setup time, EDx valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
12	^t oh(SDCLKH-EDIV)	Output hold time, EDx invalid after SDCLK high	0.5P – 2		0.5P – 1		ns
13	^t su(SDWE-SDCLKH)	Setup time, SDWE valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
14	toh(SDCLKH-SDWE)	Output hold time, SDWE valid after SDCLK high	0.5P – 2		0.5P – 1		ns
15	^t su(SDA10V-SDCLKH)	Setup time, SDA10 valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
16	^t oh(SDCLKH-SDA10IV)	Output hold time, SDA10 invalid after SDCLK high	0.5P – 2		0.5P – 1		ns
17	tsu(SDRAS-SDCLKH)	Setup time, SDRAS valid before SDCLK high	1.5P – 6		1.5P – 3.5		ns
18	toh(SDCLKH-SDRAS)	Output hold time, SDRAS valid after SDCLK high	0.5P – 2		0.5P – 1		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter or SDCLK duty cycle. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



SYNCHRONOUS DRAM TIMING (CONTINUED)





Figure 20. Three SDRAM WRT Commands



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999













SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999



SYNCHRONOUS DRAM TIMING (CONTINUED)







SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

HOLD/HOLDA TIMING

timing requirements for the HOLD/HOLDA cycles[†] (see Figure 25)

NO.	NO.		'C620	1-150	'C6201 'C6201	UNIT	
			MIN	MAX	MIN	MAX	
1	^t su(HOLDH-CKO1H)	Setup time, HOLD high before CLKOUT1 high	5*		1,5,1		ns
2	^t h(CKO1H-HOLDL)	Hold time, HOLD low after CLKOUT1 high	2*		4		ns

[†] HOLD is synchronized internally. Therefore, if setup and hold times are not met, it will either be recognized in the current cycle or in the next cycle. Thus, HOLD can be an asynchronous input.

*This parameter is not production tested.

switching characteristics for the HOLD/HOLDA cycles (see Figure 25)

NO.		PARAMETER		'C6201-150		B-150 B-200	UNIT	
			MIN	MAX	MIN	MAX		
3	^t R(HOLDL-BHZ)	Response time, HOLD low to EMIF Bus high impedance	4*	‡	4	‡	CLKOUT1 cycles	
4	^t R(BHZ-HOLDAL)	Response time, EMIF Bus high impedance to HOLDA low	1*	2*	1	NZ2	CLKOUT1 cycles	
5	^t R(HOLDH-HOLDAH)	Response time, HOLD high to HOLDA high	4*	6	4	7	CLKOUT1 cycles	
6	^t d(CKO1H-HOLDAL)	Delay time, CLKOUT1 high to HOLDA valid	-1*	5	$\mathcal{T}_{\mathcal{T}}$	8	ns	
7	^t d(CKO1H-BHZ)	Delay time, CLKOUT1 high to EMIF Bus high impedance \S	-1*	5*	03	11	ns	
8	^t d(CKO1H-BLZ)	Delay time, CLKOUT1 high to EMIF Bus low impedance $\$$	-1*	5*	Q 3	11	ns	
9	^t R(HOLDH-BLZ)	Response time, HOLD high to EMIF Bus low impedance	3*	5*	3	6	CLKOUT1 cycles	

*This parameter is not production tested.

[‡] All pending EMIF transactions are allowed to complete before HOLDA is asserted. The worst cases for this is an asynchronous read or write with external ARDY used or a minimum of eight consecutive SDRAM reads or writes when RBTR8 = 1. If no bus transactions are occurring, then the minimum delay time can be achieved. Also, bus hold can be indefinitely delayed by setting NOHOLD = 1.

SEMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.



[†] EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.

Figure 25. HOLD/HOLDA Timing

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



POST OFFICE BOX 1443 ● HOUSTON, TEXAS 77251-1443

SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

RESET TIMING

timing requirements for reset (see Figure 26)

NO.			'C6201-150		'C6201B-150 'C6201B-200		UNIT	
			MIN	MAX	MIN	MAX		
1	^t w(RST)	Width of the RESET pulse (PLL stable)	10*		10	No.	CLKOUT1 cycles	
		Width of the \overline{RESET} pulse (PLL needs to sync up) [†]	250*		250	21.	μs	

*This parameter is not production tested.

[†] The RESET signal is not connected internally to the clock PLL circuit. The PLL, however, may need up to 250 μs to stabilize following device powerup or after PLL configuration has been changed. During that time, RESET must be asserted to ensure proper device operation. See the *clock PLL* section for PLL lock times.

switching characteristics during reset[‡] (see Figure 26)

NO.		PARAMETER	'C6201-150		'C6201B-150 'C6201B-200		UNIT	
			MIN	MAX	MIN	MAX		
2	^t R(RST)	Response time to change of value in RESET signal		2		2	CLKOUT1 cycles	
3	td(CKO1H-CKO2IV)	Delay time, CLKOUT1 high to CLKOUT2 invalid	-1*	10*	-1	10	ns	
4	^t d(CKO1H-CKO2V)	Delay time, CLKOUT1 high to CLKOUT2 valid	-1*	10	-1	10	ns	
5	td(CKO1H-SDCLKIV)	Delay time, CLKOUT1 high to SDCLK invalid	-1*	10*	-1	10	ns	
6	td(CKO1H-SDCLKV)	Delay time, CLKOUT1 high to SDCLK valid	-1*	10	-1	10	ns	
7	td(CKO1H-SSCKIV)	Delay time, CLKOUT1 high to SSCLK invalid	-1*	10*	-1	<u>i</u> 10	ns	
8	td(CKO1H-SSCKV)	Delay time, CLKOUT1 high to SSCLK valid	-1*	10	-1,9	10	ns	
9	^t d(CKO1H-LOWIV)	Delay time, CLKOUT1 high to low group invalid	-1*	10*	. Т	10	ns	
10	^t d(CKO1H-LOWV)	Delay time, CLKOUT1 high to low group valid	-1*		4		ns	
11	td(CKO1H-HIGHIV)	Delay time, CLKOUT1 high to high group invalid	-1*	10*	<i>S</i> −1	10	ns	
12	^t d(CKO1H-HIGHV)	Delay time, CLKOUT1 high to high group valid	-1*		-1		ns	
13	td(CKO1H-ZHZ)	Delay time, CLKOUT1 high to Z group high impedance	-1*	10*	-1	10	ns	
14	^t d(CKO1H-ZV)	Delay time, CLKOUT1 high to Z group valid	-1*		-1		ns	

[‡] Low group consists of: IA

High group consists of: Z group consists of: ACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1

s of: HRDY and HINT

<u>EA[21:2]</u>, ED[31:0], <u>CE[3:0]</u>, <u>BE[3:0]</u>, <u>ARE</u>, <u>AWE</u>, <u>AOE</u>, <u>SSADS</u>, <u>SSOE</u>, <u>SSWE</u>, SDA10, <u>SDRAS</u>, <u>SDCAS</u>, <u>SDWE</u>, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

*This parameter is not production tested.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999



RESET TIMING (CONTINUED)

Figure 26. Reset Timing



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

EXTERNAL INTERRUPT/RESET TIMING

timing requirements for interrupt response cycles[†] (see Figure 27)

NO.	0.		'C6201-150		'C6201B-150 'C6201B-200		UNIT	
		Γ	MIN	MAX	MIN	MAX		
3	t _w (ILOW) Width of the interrupt pulse low		2		2	5	CLKOUT1 cycles	
4	tw(IHIGH) Width of the interrupt pulse high		2		2	MENT	CLKOUT1 cycles	

[†] Interrupt signals are synchronized internally and are potentially recognized one cycle later if setup and hold times are violated. Thus, they can be connected to asynchronous inputs.

switching characteristics during interrupt response cycles (see Figure 27)

NO.	PARAMETER		'C6201-150		'C6201B-150 'C6201B-200		UNIT
		MIN	MAX	MIN	MAX		
1	^t R(EINTH-IACKH)	Response time, EXT_INTx high to IACK high	9‡*		9‡	5W	CLKOUT1 cycles
2	^t R(ISFP)	Response time, interrupt service fetch packet execution after EXT_INTx high	11‡*		11‡	REN	CLKOUT1 cycles
5	td(CKO2L-IACKV)	Delay time, CLKOUT2 low to IACK valid	0*	10	0	10	ns
6	td(CKO2L-INUMV)	Delay time, CLKOUT2 low to INUMx valid	0*	10	0	10	ns
7	td(CKO2L-INUMIV)	Delay time, CLKOUT2 low to INUMx invalid	0*	10*	% 0	10	ns

‡Add two CLKOUT1 cycles to this parameter if the interrupt is recognized during the high half of CLKOUT2

*This parameter is not production tested.





SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

HOST-PORT INTERFACE TIMING

timing requirements for host-port interface cycles[†] (see Figure 28, Figure 29, Figure 30, and Figure 31)

NO.			'C620	'C6201-150		1B-150 1B-200	UNIT
			MIN	MAX	MIN	MAX	
1	t _{su} (SEL-HSTBL)	Setup time, select signals [‡] valid before HSTROBE low	1		1		ns
2	^t h(HSTBL-SEL)	Hold time, select signals [‡] valid after HSTROBE low	2		2		ns
3	^t w(HSTBL)	Pulse duration, HSTROBE low	2		2	2	CLKOUT1 cycles
4	^t w(HSTBH)	Pulse duration, HSTROBE high between consecutive accesses	2*		2	REVIE	CLKOUT1 cycles
10	t _{su} (SEL-HASL)	Setup time, select signals [‡] valid before HAS low	1		1	2	ns
11	^t h(HASL-SEL)	Hold time, select signals [‡] valid after HAS low	2		25		ns
12	t _{su} (HDV-HSTBH)	Setup time, host data valid before HSTROBE high	1		8		ns
13	^t h(HSTBH-HDV)	Hold time, host data valid after HSTROBE high	1		Q 1		ns
14	^t h(HRDYL-HSTBL)	Hold time, HSTROBE low after HRDY low. HSTROBE should not be inactivated until HRDY is active (low); otherwise, HPI writes will not complete properly.	1*		1		ns

† HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS. [‡] Select signals include: HCNTRL[1:0], HR/W, and HHWIL.

*This parameter is not production tested.

switching characteristics during host-port interface cycles^{†§} (see Figure 28, Figure 29, Figure 30, and Figure 31)

NO.	PARAMETER		'C620	1-150	'C6201 'C6201	UNIT	
				MAX	MIN	MAX	
5	^t d(HCS-HRDY)	Delay time, HCS to HRDY¶	1*	7*	1	7	ns
6	^t d(HSTBL-HRDYH)	Delay time, HSTROBE low to HRDY high#	3*	12*	3	12	ns
7	^t oh(HSTBL-HDLZ)	Output hold time, HD low impedance after HSTROBE low for an HPI read	4*		4	VIEW	ns
8	^t d(HDV-HRDYL)	Delay time, HD valid to HRDY low	P – 3*	P*	P – 2	P	ns
9	toh(HSTBH-HDV)	Output hold time, HD valid after HSTROBE high	3*	12*	3	12	ns
15	^t d(HSTBH-HDHZ)	Delay time, HSTROBE high to HD high impedance	3*	12*	3	12	ns
16	^t d(HSTBL-HDV)	Delay time, HSTROBE low to HD valid	3*	12*	2 3	12	ns
17	^t d(HSTBH-HRDYH)	Delay time, HSTROBE high to HRDY high	3*	12*	3	12	ns

[†]HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

§ The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns. I HCS enables HRDY, and HRDY is always low when HCS is high. The case where HRDY goes high when HCS falls indicates that HPI is busy

completing a previous HPID write or READ with autoincrement.

*This parameter is not production tested.

This parameter is used during an HPID read. At the beginning of the first half-word transfer on the falling edge of HSTROBE, the HPI sends the request to the DMA auxiliary channel, and HRDY remains high until the DMA auxiliary channel loads the requested data into HPID.

I This parameter is used after the second half-word of an HPID write or autoincrement read. HRDY remains low if the access is not an HPID write or autoincrement read. Reading or writing to HPIC or HPIA does not affect the HRDY signal.



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



HOST-PORT INTERFACE TIMING (CONTINUED)

† HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 28. HPI Read Timing (HAS Not Used, Tied High)





POST OFFICE BOX 1443 • HOUSTON, TEXAS 77251-1443

SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999



HOST-PORT INTERFACE TIMING (CONTINUED)

Figure 30. HPI Write Timing (HAS Not Used, Tied High)





SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING

timing requirements for McBSP^{†‡}(see Figure 32)

NO.					1-150	'C6201B-150 'C6201B-200		UNIT
				MIN	MAX	MIN	MAX	
2	^t c(CKRX)	Cycle time, CLKR/X	CLKR/X ext	2*		2		CLKOUT1 cycles
3	^t w(CKRX)	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X ext	P – 1*		P – 1		ns
5	•	Setup time, external FSR high before	CLKR int	13		9		20
5	ⁱ su(FRH-CKRL)	CLKR low	CLKR ext	4		1		115
6	t. (0)(7). 77)	Hold time, external FSR high after CLKR	CLKR int	7*		6	IEI	20
0	^ı h(CKRL-FRH)	low	CLKR ext	3.5		3	IEL	115
7		Satur time, DB valid before CLKP law	CLKR int	13.5		8	2	20
'	'su(DRV-CKRL)	Setup time, DR valid before CERR fow	CLKR ext	1		0	,	115
		Light time, DD valid after CLKD low	CLKR int	4*		3		
°	ⁱ h(CKRL-DRV)	Hold liffle, DR valid after CERR low	CLKR ext	4		\$ 3		115
10	t (=) () () () () () () () () () () () () ()	Setup time, external FSX high before	CLKX int	13		9		20
10	'su(FXH-CKXL)	CLKX low	CLKX ext	4		1		115
11		Hold time, external FSX high after CLKX	CLKX int	7		6		
	^t h(CKXL-FXH)	low	CLKX ext	3.5		3		115

[†] CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted. [‡] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter or SSCLK duty cycle. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

*This parameter is not production tested.



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

switching characteristics for McBSP^{†‡} (see Figure 32)

NO.		PARAMETER (C6201-150 MIN M		'C6201-150		'C6201B-150 'C6201B-200		UNIT
				MAX	MIN	MAX		
1	^t d(CKSH-CKRXH)	Delay time, CLKS high to CLKR/X high for internal CLKR/X generated from CLKS input		4*	15*	4	10	ns
2	^t c(CKRX)	Cycle time, CLKR/X	CLKR/X int	2*		2		CLKOUT1 cycles
3	^t w(CKRX)	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X int	C – 1*¶	C + 1*¶	C – 1¶	C + 1¶	ns
4	^t d(CKRH-FRV)	Delay time, CLKR high to internal FSR valid	CLKR int	-2*	4.5*	-2	3	ns
0	t.v.a.a	Delay time, CLKX high to internal	CLKX int	0*	4*	-2	3	20
9	^t d(CKXH-FXV)	FSX valid	CLKX ext	3*	16	3	9	ns
40		Disable time, DX high impedance	CLKX int	0*	4*	-1	4	
12	^t dis(CKXH-DXHZ)	dis(CKXH-DXHZ) following last data bit from CLKX high	CLKX ext	3*	16*	3	2 9	ns
		Delay time, CLKX high to DX valid This is also specified by design but	CLKX int	0*	4*	⁹ 000	4	
13	^t d(CKXH-DXV)	not tested to be the delay time for data to be low impedance on the first data bit.	CLKX ext	3*	16	3	9	ns
		Delay time, FSX high to DX valid						
14	·	This is also specified by design but not tested to be the delay time for	FSX int	-2*	4*	-1	3	20
14	^t d(FXH-DXV)	(FXH-DXV) data to be low impedance on the first data bit. ONLY applies when in data delay 0 (XDATDLY = 00b) mode	FSX ext	3*	16*	3	9	115

CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted. [‡] Minimum delay times also represent minimum output hold times. *This parameter is not production tested.

¶C = HorL

H = CLKX high pulse width = (CLKGDV/2 + 1) * T L = CLKX low pulse width = (CLKGDV/2) * T



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

Figure 32. McBSP Timings



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for FSR when GSYNC = 1 (see Figure 33)

NO.	NO.		1-150	'C6201 'C6201	UNIT	
		MIN	MAX	MIN	MAX	
1	tsu(FRH-CKSH) Setup time, FSR high before CLKS high	4*		4		ns
2	th(CKSH-FRH) Hold time, FSR high after CLKS high	4*		4	2.	ns
				0.		

*This parameter is not production tested.



Figure 33. FSR Timing When GSYNC = 1



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 0^{+1} (see Figure 34) ('C6201)

			'C620	1-150		
NO.		MAS	TER	SLA	/E	UNIT
		MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXL)} Setup time, DR valid before CLKX low	12		3P – 2*		ns
5	th(CKXL-DRV) Hold time, DR valid after CLKX low	4*		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency. in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1. *This parameter is not production tested.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 0^{†‡} (see Figure 34) ('C6201)

				'Ce	6201-150		
NO.		PARAMETER	MAS	TER§	SLA	AVE	UNIT
			MIN	MAX	MIN	MAX	
1	^t h(CKXL-FXL)	Hold time, FSX low after CLKX low¶	T – 2*	T + 3*			ns
2	^t d(FXL-CKXH)	Delay time, FSX low to CLKX high [#]	L – 2*	L + 3*			ns
		Delay time, CLKX high to DX valid					
3	^t d(CKXH-DXV)	This is also specified by design but not tested to be the delay time for data to be low impedance on the first data bit.	-2*	4*	3P + 4*	5P + 17*	ns
6	^t dis(CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	L – 2*	L + 3*			ns
7	^t dis(FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high			P + 4*	3P + 17*	ns
8	td(FXL-DXV)	Delay time, FSX low to DX valid			2P + 4*	4P + 17	ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡]For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency = CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

*This parameter is not production tested.

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 0^{†‡} (see Figure 34) ('C6201B)

NO.		MAST	ER	SLA\	/E	UNIT
		MIN	MAX	MIN	MAX	
4	tsu(DRV-CKXL) Setup time, DR valid before CLKX low	12		3P – 2		ns
5	th(CKXL-DRV) Hold time, DR valid after CLKX low	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡]For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 0^{†‡} (see Figure 34) ('C6201B)

NO.		PARAMETER	MAS	ΓER§	SL/	AVE	
			MIN	MAX	MIN	MAX	
1	^t h(CKXL-FXL)	Hold time, FSX low after CLKX low \P	T – 2	T + 3			ns
2	^t d(FXL-CKXH)	Delay time, FSX low to CLKX high [#]	L – 2	L+3			ns
3	^t d(CKXH-DXV)	Delay time, CLKX high to DX valid This is also specified by design but not tested to be the delay time for data to be low impedance on the first data bit.	-2	4	3P + 4	5P + 17	ns
6	^t dis(CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	L – 2	L+3			ns
7	^t dis(FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high			P+3	3P + 17	ns
8	td(FXL-DXV)	Delay time, FSX low to DX valid			2P + 2	4P + 17	ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡]For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency = CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999









SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0^{1+} (see Figure 35) ('C6201)

			'C620	1-150		
NO.		MAST	ER	SLA\	/E	UNIT
		MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXH)} Setup time, DR valid before CLKX high	11		3P – 2		ns
5	th(CKXH-DRV) Hold time, DR valid after CLKX high	4*		5 + 6P*		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

*This parameter is not production tested.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0^{†‡} (see Figure 35) ('C6201)

	PARAMETER						
NO.			MAS	TER§	SL/	UNIT	
			MIN	MAX	MIN	MAX	
1	^t h(CKXL-FXL)	Hold time, FSX low after CLKX low¶	L – 2*	L + 3*			ns
2	^t d(FXL-CKXH)	Delay time, FSX low to CLKX high [#]	T – 2*	T + 4.5*			ns
3	^t d(CKXL-DXV)	Delay time, CLKX low to DX valid	-2*	4*	3P + 4*	5P + 17*	ns
6	^t dis(CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	-2*	4*	3P + 4*	5P + 17*	ns
7	td(FXL-DXV)	Delay time, FSX low to DX valid	H – 2*	H + 4*	2P + 4*	4P + 17*	ns

⁺ The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency

= CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

*This parameter is not production tested.

[#] FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0^{\pm} (see Figure 35) ('C6201B)

NO.			'C6201 'C6201	B-150 B-200		
		MASTER		SLAVE		UNIT
		MIN	MAX	MIN	MAX	
4	tsu(DRV-CKXH) Setup time, DR valid before CLKX high	12		3P – 2		ns
5	th(CKXH-DRV) Hold time, DR valid after CLKX high	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0^{†‡} (see Figure 35) ('C6201B)

NO.							
	PARAMETER			ΓER§	SLA	UNIT	
				MAX	MIN	MAX	
1	^t h(CKXL-FXL)	Hold time, FSX low after CLKX low	L – 2	L+3			ns
2	^t d(FXL-CKXH)	Delay time, FSX low to CLKX high [#]	T – 2	T + 3			ns
3	^t d(CKXL-DXV)	Delay time, CLKX low to DX valid	-2	4	3P + 4	5P + 17	ns
6	^t dis(CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	-2	4	3P + 3	5P + 17	ns
7	td(FXL-DXV)	Delay time, FSX low to DX valid	H – 2	H + 4	2P + 2	4P + 17	ns

⁺ The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency = CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

IFSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999







SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{\ddagger} (see Figure 36) ('C6201)

			'C620	1-150		
NO.		MASTER		SLAVE		UNIT
		MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXH)} Setup time, DR valid before CLKX high	12*		3P – 2		ns
5	th(CKXH-DRV) Hold time, DR valid after CLKX high	4*		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1. *This parameter is not production tested.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{†‡} (see Figure 36) ('C6201)

				'C620	01-150		
NO.		PARAMETER	MAS	TER§	SL	AVE	UNIT
			MIN	MAX	MIN	MAX	
1	^t h(CKXH-FXL)	Hold time, FSX low after CLKX high \P	T – 2*	T + 3*			ns
2	td(FXL-CKXL)	Delay time, FSX low to CLKX low [#]	H – 2*	H + 4.5*			ns
3	^t d(CKXL-DXV)	Delay time, CLKX low to DX valid This is also specified by design but not tested to be the delay time for data to be low impedance on the first data bit.	-2*	4*	3P + 4*	5P + 17*	ns
6	^t dis(CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	H – 2*	H + 3*			ns
7	^t dis(FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high			P + 4*	3P + 17*	ns
8	td(FXL-DXV)	Delay time, FSX low to DX valid			2P + 4*	4P + 17*	ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡]For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

\$T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency

= CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

IFSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

*This parameter is not production tested.

[#] FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{\ddagger} (see Figure 36) ('C6201B)

NO.			'C6201 'C6201	B-150 B-200		
			MASTER		SLAVE	
			MAX	MIN	MAX	
4	tsu(DRV-CKXH) Setup time, DR valid before CLKX high	12		3P – 2		ns
5	th(CKXH-DRV) Hold time, DR valid after CLKX high	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{†‡} (see Figure 36) ('C6201B)

NO.		MAS	TER§	SL/	AVE		
			MIN	MAX	MIN	MAX	
1	^t h(CKXH-FXL)	Hold time, FSX low after CLKX high \P	T – 2	T + 3			ns
2	^t d(FXL-CKXL)	Delay time, FSX low to CLKX low#	H – 2	H + 3			ns
3	^t d(CKXL-DXV)	Delay time, CLKX low to DX valid This is also specified by design but not tested to be the delay time for data to be low impedance on the first data bit.	-2	4	3P + 4	5P + 17	ns
6	^t dis(CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	H – 2	H + 3			ns
7	^t dis(FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high			P + 3	3P + 17	ns
8	td(FXL-DXV)	Delay time, FSX low to DX valid			2P + 2	4P + 17	ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency

= CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

IFSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

[#] FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999









SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{\ddagger} (see Figure 37) ('C6201)

			'C620	1-150		
NO.		MAST	FER	SLA\	/E	UNIT
		MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXL)} Setup time, DR valid before CLKX low	11		3P – 2		ns
5	th(CKXL-DRV) Hold time, DR valid after CLKX low	4.5		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{†‡} (see Figure 37) ('C6201)

	PARAMETER						
NO.			MASTER§		SLA	UNIT	
			MIN	MAX	MIN	MAX	
1	^t h(CKXH-FXL)	Hold time, FSX low after CLKX high \P	H – 2*	H + 3*			ns
2	^t d(FXL-CKXL)	Delay time, FSX low to CLKX low [#]	T – 2*	T + 1*			ns
3	^t d(CKXH-DXV)	Delay time, CLKX high to DX valid	-2*	4*	3P + 4*	5P + 17	ns
6	^t dis(CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	-2*	4*	3P + 4*	5P + 17*	ns
7	^t d(FXL-DXV)	Delay time, FSX low to DX valid	L – 2*	L + 4*	2P + 4*	4P + 17*	ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency

= CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

*This parameter is not production tested.

[#] FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{†‡} (see Figure 37) ('C6201B)

NO.			'C620′ 'C620′	B-150 B-200		
		MASTER		SLAVE		UNIT
		MIN	MAX	MIN	MAX	
4	tsu(DRV-CKXL) Setup time, DR valid before CLKX low	12		3P – 2		ns
5	th(CKXL-DRV) Hold time, DR valid after CLKX low	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{†‡} (see Figure 37) ('C6201B)

NO.								
	PARAMETER			MASTER§		SLAVE		
				MAX	MIN	MAX		
1	^t h(CKXH-FXL)	Hold time, FSX low after CLKX high	H – 2	H + 3			ns	
2	td(FXL-CKXL)	Delay time, FSX low to CLKX low [#]	T – 2	T + 1			ns	
3	^t d(CKXH-DXV)	Delay time, CLKX high to DX valid	-2	4	3P + 4	5P + 17	ns	
6	^t dis(CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	-2	4	3P + 3	5P + 17	ns	
7	td(FXL-DXV)	Delay time, FSX low to DX valid	L-2	L+4	2P + 2	4P + 17	ns	

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 150 MHz, use P = 6.67 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§T = CLKX period = (1 + CLKGDV) * P; if CLKSM = 1, then P = 1/CPU clock frequency = CLKX period = (1 + CLKGDV) * P_clks; if CLKSM = 0, then P_clks = CLKS period.

H = CLKX high pulse width = (CLKGDV/2 + 1) * T

L = CLKX low pulse width = (CLKGDV/2) * T

IFSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999



Figure 37. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 1



SGUS028A – NOVEMBER 1998 – REVISED JANUARY 1999

DMAC, TIMER, POWER-DOWN TIMING

switching characteristics for DMAC outputs (see Figure 38)

NO.	PARAMETER		'C6201-150		'C6201B-150 'C6201B-200		UNIT
		MIN	MAX	MINSS	MAX		
1	^t d(CKO1H-DMACV)	Delay time, CLKOUT1 high to DMAC valid	2*	7*	2	7	ns
*This pa	rameter is not productio	on tested.			64		
	CLKOUT1 /					/	
I	DMAC[0:3]	///////					

Figure 38. DMAC Timing

timing requirements for timer inputs (see Figure 39)

NO.			'C6201-150		'C6201B-150 'C6201B-200	UNIT	
			MIN	MAX	MIN CMAX		
1	^t w(TINP)	Pulse duration, TINP high or low	2		2 Plant	CLKOUT1 cycles	

switching characteristics for timer outputs (see Figure 39)

NO.	PARAMETER		'C6201-150		'C6201B-150 'C6201B-200		UNIT
			MIN	MAX	MIN MAX		
2	^t d(CKO1H-TOUTV)	Delay time, CLKOUT1 high to TOUT valid	3*	9	3	9	ns
*Thic po	romotor is not productio	on tostad			Q.		

*This parameter is not production tested.



Figure 39. Timer Timing



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

DMAC, TIMER, POWER-DOWN TIMING (CONTINUED)

switching characteristics for power-down outputs (see Figure 40)





SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MECHANICAL DATA

GLE (S-CBGA-N429)

CERAMIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-156
- D. For 320C6201 (2.5 V core device).
- E. Package weight for GLE is 7.65 grams.

thermal resistance characteristics (S-CBGA package)

NO		°C/W	Air Flow
1	R _{OJC} Junction-to-Case	1.7	N/A
2	R _{OJA} Junction-to-Ambient	14.4	0



SGUS028A - NOVEMBER 1998 - REVISED JANUARY 1999

MECHANICAL DATA

GLP (S-CBGA-N429)

CERAMIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

- C. Falls within JEDEC MO-156
- D. Flip chip application only
- E. For 320C6201B (1.8 V core device).

F. Package weight for GLP is 7.65 grams.

thermal resistance characteristics (S-CBGA package)

NO		°C/W	Air Flow
1	R _{OJC} Junction-to-Case	1.7	N/A
2	ROJA Junction-to-Ambient	14.4	0


IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1999, Texas Instruments Incorporated